

<b>FORM PTO-1449</b>				<b>Atty. Docket No.</b> XA-10070		<b>Appl. No.</b> 10/829,300	
<b>LIST OF DOCUMENTS CITED BY APPLICANT</b>				<b>Applicant</b> Yuichi MATSUI			
				<b>Filing Date</b> HEREWITH		<b>Group</b> 2818	
<b>U.S. PATENT DOCUMENTS</b>							
Examiner Initial		Document Number	Date	Name	Class	Sub-class	Filing Date
TH	AA	5,622,888	4/22/97	Sekine et al.	438	398	—
	AB	6,235,572	5/22/01	Kunitomo et al.	438	240	—
	AC	6,243,255	6/5/01	Kuge et al.	361	528	—
	AD	2003/0011022	1/16/03	Manabe	257	314	—
	AE	6,576,928	6/10/03	Hiratani et al.	257	68	—
	AF	6,673,461	1/6/04	Chazono et al.	428	469	—
	AG	5,970,337	10/19/99	Nishioka	438	240	—
TH	AH	2003-0151083	8/14/03	Matsui et al.	257	310	—
	AI						
<b>FOREIGN PATENT DOCUMENTS</b>							
Examiner Initial		Document Number	Date	Country	Class	Sub-class	Translation
TH	AJ	8-139288	5/31/96	JAPAN	—	—	abstract
	AK	2000-12796	1/14/00	JAPAN	—	—	abstract
	AL	2000-82639	3/21/00	JAPAN	—	—	abstract
	AM	2002-164516	6/7/02	JAPAN	—	—	abstract
	AN	2003-243534	8/29/03	JAPAN	—	—	abstract
TH	AO	2001-77108	3/23/01	JAPAN	—	—	abstract
<b>OTHER (including author, title, date, pertinent pages, etc.)</b>							
TH	AP	Rosenfeld, D. et al., "Structural and morphological characterization of Nb <sub>2</sub> O <sub>5</sub> thin films deposited by reactive sputtering", <u>American Vacuum Society</u> , 1994, pp. 135-139.					
	AQ						
	AR						
<b>Examiner</b> TH - TH +10				<b>Date Considered</b> Oct 2005			
EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to Applicant.							

Best Available Copy

<b>FORM PTO-1449</b>				<b>Atty. Docket No.</b> XA-10070		<b>Appln. No.</b> 10/829,300	
<b><u>LIST OF DOCUMENTS CITED BY APPLICANT</u></b>				<b>Applicant</b> Yuichi MATSUI			
				<b>Filing Date</b> HEREWITH		<b>Group</b> 2818	
<b>U.S. PATENT DOCUMENTS</b>							
<b>Examiner Initial</b>		<b>Document Number</b>	<b>Date</b>	<b>Name</b>	<b>Class</b>	<b>Sub-class</b>	<b>Filing Date</b>
	BA						
	BB						
	BC						
	BD						
	BE						
	BF						
	BG						
	BH						
	BI						
<b>FOREIGN PATENT DOCUMENTS</b>							
<b>Examiner Initial</b>		<b>Document Number</b>	<b>Date</b>	<b>Country</b>	<b>Class</b>	<b>Sub-class</b>	<b>Translation</b>
JH	BJ	5-345663	12/27/93	JAPAN	—	—	abstract
	BK	10-12043	1/16/98	JAPAN	—	—	abstract
	BL	2001-284158	10/12/01	JAPAN	—	—	abstract
	BM	8-31951	2/2/96	JAPAN	—	—	abstract
JH	BN	11-330415	11/30/99	JAPAN	—	—	abstract
	BO						
<b>OTHER (including author, title, date, pertinent pages, etc.)</b>							
	BP						
	BQ						
	BR						
<b>Examiner</b> TU-TU +10				<b>Date Considered</b> Oct 2005			
<b>EXAMINER:</b> Initial if reference considered, whether or not citation is in conformance with MPEP 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to Applicant.							

Best Available Copy